

## EAST Search History

| Ref # | Hits | Search Query  | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|---|---|------------------|---------|------------------|
| L1    | 764  | (scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) and ((isolat\$4 or identif\$5 or reject\$3 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3)) and (correct\$3 or modif\$5) and (test\$3 near2 mode\$1)  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/11/09 14:09 |
| L2    | 42   | (scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) and ((isolat\$4 or identif\$5 or reject\$3 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3)) and (correct\$3 or modif\$5) and (test\$3 near2 mode\$1) and (lssd or (level adj1 sensitive adj1 scan adj1 design)) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/11/09 13:16 |
| L3    | 10   | (scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) same ((isolat\$4 or identif\$5 or reject\$3 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3)) same (correct\$3 or modif\$5) same (test\$3 near2 mode\$1)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/11/09 14:11 |
| L4    | 24   | (scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) same ((isolat\$4 or identif\$5 or reject\$3 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3)) same (test\$3 near2 mode\$1)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/11/09 14:11 |
| L5    | 542  | (scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) and ((isolat\$4 or identif\$5 or reject\$3 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3)) and (test adj2 mode\$1)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/11/09 14:12 |
| L6    | 542  | ((scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) and (test adj2 mode\$1)) and ((isolat\$4 or identif\$5 or reject\$3 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3))   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/11/09 14:13 |

## EAST Search History

|     |     |  |   |    |     |                  |
|-----|-----|--|---|----|-----|------------------|
| L7  | 285 | ((scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) same (test adj2 mode\$1)) and ((isolat\$4 or identif\$5 or reject\$3 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3)) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/11/09 14:13 |
| L8  | 168 | ((scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) same (test adj2 mode\$1)) and ((isolat\$4 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3))                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/11/09 14:14 |
| L9  | 31  | ((scan\$4 near4 (chain\$1 or register\$1 or latch\$3 or flip-flop\$1 or test\$3)) same (test adj2 modes)) and ((isolat\$4 or separat\$4) near3 (defect\$2 or erro\$4 or fail\$3))                              | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/11/09 14:23 |
| L10 | 697 | (first adj2 (test or scan or capture) adj2 mode) and (second adj2 (test or scan or capture) adj2 mode)   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/11/09 14:25 |
| L12 | 8   | (first adj2 (test or scan or capture) adj2 mode) same (second adj2 (test or scan or capture) adj2 mode) same modif\$5  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/11/09 14:26 |
| L13 | 120 | ((first adj2 (test or scan or capture) adj2 mode) same (second adj2 (test or scan or capture) adj2 mode)) and modif\$5   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/11/09 14:27 |

 PALM INTRANETDay : Thursday  
Date: 11/9/2006  
Time: 11:07:54

## Inventor Information for 10/708380

| Inventor Name        | City                | State/Country |
|----------------------|---------------------|---------------|
| HUISMAN, LEENDERT M. | SOUTH BURLINGTON    | VERMONT       |
| HUISMAN, LEENDERT M. | SOUTH BURLINGTON    | VERMONT       |
| HUOTT, WILLIAM V.    | HOLMES              | NEW YORK      |
| HUOTT, WILLIAM V.    | HOLMES              | NEW YORK      |
| KASSAB, MAROUN       | ST-EUSTACHE, QUEBEC | CANADA        |
| KASSAB, MAROUN       | ST-EUSTACHE, QUEBEC | CANADA        |
| MOTIKA, FRANCO       | HOPEWELL JUNCTION   | NEW YORK      |
| MOTIKA, FRANCO       | HOPEWELL JUNCTION   | NEW YORK      |

[Appln Info](#)[Contents](#)[Petition Info](#)[Atty/Agent Info](#)[Continuity/Reexam](#)[Foreign Data](#)Search Another: Application#   or Patent#  PCT /  /   or PG PUBS #  Attorney Docket #  Bar Code #  

To go back use Back button on your browser toolbar.

Back to [PALM](#) | [ASSIGNMENT](#) | [OASIS](#) | [Home page](#)


**PALM INTRANET**

 Day : Thursday  
 Date: 11/9/2006  
 Time: 11:07:57
**Inventor Name Search Result**

Your Search was:

Last Name = HUISMAN

First Name = LEENDERT

| Application#             | Patent#                 | Status | Date Filed | Title  | Inventor Name        |
|--------------------------|-------------------------|--------|------------|--|----------------------|
| <a href="#">09524254</a> | <a href="#">6931580</a> | 150    | 03/13/2000 | RAPID FAIL ANALYSIS OF EMBEDDED OBJECTS  | HUISMAN, LEENDERT M. |
| <a href="#">09682456</a> | <a href="#">6675323</a> | 150    | 09/05/2001 | INCREMENTAL FAULT DICTIONARY   | HUISMAN, LEENDERT M. |
| <a href="#">09827425</a> | <a href="#">6721914</a> | 150    | 04/06/2001 | DIAGNOSIS OF COMBINATIONAL LOGIC CIRCUIT FAILURES  | HUISMAN, LEENDERT M. |
| <a href="#">09927011</a> | <a href="#">6901542</a> | 150    | 08/09/2001 | INTERNAL CACHE FOR ON CHIP TEST DATA STORAGE   | HUISMAN, LEENDERT M. |
| <a href="#">09930355</a> | <a href="#">6671644</a> | 150    | 08/15/2001 | USING CLOCK GATING OR SIGNAL GATING TO PARTITION A DEVICE FOR FAULT ISOLATION AND DIAGNOSTIC DATA COLLECTION | HUISMAN, LEENDERT M. |
| <a href="#">10191212</a> | <a href="#">6880136</a> | 150    | 07/09/2002 | METHOD TO DETECT SYSTEMATIC DEFECTS IN VLSI MANUFACTURING  | HUISMAN, LEENDERT M. |
| <a href="#">10604179</a> | <a href="#">6954916</a> | 150    | 06/30/2003 | METHODOLOGY FOR FIXING QCRIT AT DESIGN TIMING IMPACT   | HUISMAN, LEENDERT M. |
| <a href="#">10697365</a> | <a href="#">6865501</a> | 150    | 10/30/2003 | USING CLOCK GATING OR SIGNAL GATING TO PARTITION A DEVICE FOR FAULT ISOLATION AND DIAGNOSTIC DATA COLLECTION | HUISMAN, LEENDERT M. |
| <a href="#">10707373</a> | Not Issued              | 41     | 12/09/2003 | SCAN CHAIN DIAGNOSTICS USING LOGIC PATHS   | HUISMAN, LEENDERT M. |
| <a href="#">10707957</a> | <a href="#">7139950</a> | 150    | 01/28/2004 | SEGMENTED SCAN CHAINS WITH DYNAMIC RECONFIGURATIONS  | HUISMAN, LEENDERT M. |
| <a href="#">10708380</a> | Not Issued              | 30     | 02/27/2004 | METHODS AND APPARATUS FOR DEFECT ISOLATION   | HUISMAN, LEENDERT M. |

|                          |                         |     |            |  |                           |
|--------------------------|-------------------------|-----|------------|--|---------------------------|
| <a href="#">10709672</a> | Not Issued              | 30  | 05/21/2004 | LEARNING BASED LOGIC DIAGNOSIS   | HUISMAN, LEENDERT M.      |
| <a href="#">10710642</a> | Not Issued              | 93  | 07/27/2004 | DESIGNING SCAN CHAINS WITH SPECIFIC PARAMETER SENSITIVITIES TO IDENTIFY PROCESS DEFECTS                      | HUISMAN, LEENDERT M.      |
| <a href="#">10710879</a> | <a href="#">7089514</a> | 150 | 08/10/2004 | DEFECT DIAGNOSIS FOR SEMICONDUCTOR INTEGRATED CIRCUITS   | HUISMAN, LEENDERT M.      |
| <a href="#">10711765</a> | Not Issued              | 41  | 10/04/2004 | INSPECTION METHODS AND STRUCTURES FOR VISUALIZING AND/OR DETECTING SPECIFIC CHIP STRUCTURES                  | HUISMAN, LEENDERT M.      |
| <a href="#">11006274</a> | Not Issued              | 41  | 12/07/2004 | Using clock gating or signal gating to partition a device for fault isolation and diagnostic data collection | HUISMAN, LEENDERT M.      |
| <a href="#">06862950</a> | <a href="#">4726023</a> | 150 | 05/14/1986 | DETERMINATION OF TESTABILITY OF COMBINED LOGIC END MEMORY BY IGNORING MEMORY                                 | HUISMAN, LEENDERT M.      |
| <a href="#">07900706</a> | <a href="#">5297151</a> | 250 | 06/17/1992 | ADJUSTABLE WEIGHTED RANDOM TEST PATTERN GENERATOR FOR LOGIC CIRCUITS   | HUISMAN, LEENDERT M.      |
| <a href="#">08811605</a> | <a href="#">6519725</a> | 150 | 03/04/1997 | DIAGNOSIS OF RAMS USING FUNCTIONAL PATTERNS  | HUISMAN, LEENDERT M.      |
| <a href="#">09032567</a> | <a href="#">6170078</a> | 150 | 02/27/1998 | FAULT SIMULATION USING DYNAMICALLY ALTERABLE BEHAVIORAL MODELS   | HUISMAN, LEENDERT M.      |
| <a href="#">09379772</a> | <a href="#">6785413</a> | 150 | 08/24/1999 | RAPID DEFECT ANALYSIS BY PLACEMENT OF TESTER FAIL DATA   | HUISMAN, LEENDERT M.      |
| <a href="#">09026286</a> | <a href="#">6125461</a> | 150 | 02/19/1998 | METHOD FOR IDENTIFYING LONG PATHS IN INTEGRATED CIRCUITS   | HUISMAN, LEENDERT MARINUS |

Inventor Search Completed: No Records to Display.

|                          |                                      |                                       |                                       |
|--------------------------|--------------------------------------|---------------------------------------|---------------------------------------|
| Search Another: Inventor | Last Name                            | First Name                            | <input type="button" value="Search"/> |
|                          | <input type="text" value="HUISMAN"/> | <input type="text" value="LEENDERT"/> |                                       |

To go back use Back button on your browser toolbar.

Back to [PALM](#) | [ASSIGNMENT](#) | [OASIS](#) | [Home page](#)